

<b>Notice of References Cited</b>	Application/Control No. 10/525,822		Applicant(s)/Patent Under Reexamination NAGAYAMA ET AL.	
	Examiner Mariceli Santiago		Art Unit 2879	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,637,532	01-1972	Ramisch et al.	252/520.1
*	B	US-3,932,313	01-1976	Reynolds et al.	252/520.21
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	CIRCUIT DESIGNER'S NOTEBOOK, Dielectric Aging Phenomena. Excerpt from complete Circuit Designer's Notebook, Documnet #001-927, Rev E 1/05
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.